

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/274,015	HEBERT ET AL.
	Examiner	Art Unit
	EDMUND H. LEE	1732

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
264	255	2/6/2006	EHL
	275		
	279.1		